

**METROLOGY AND INSTRUMENTATION**

Wednesday, May 23 / 10:40 am – 12:00 pm / Room 102

**Chair:**

**Thomas G. Fiske**, *Rockwell Collins Display Systems, San Jose, CA, U.S.A.*

**Co-Chair:**

**Frank F. Rochow**, *LMT Lichtmesstechnik GmbH, Berlin, Germany*

**20.1: Invited Paper: Metrology and Robustness of Bright-Room Contrast Measurements (10:40)**

*E. Kelley*  
*NIST, Boulder, CO, U.S.A.*

Two fundamental approaches for flat-panel-display contrast characterization were explored. One method uses a directed source and the other uses diffuse illumination. How different display reflection properties respond to these two methods were calculated and consideration was given to the size of the illumination source and environment.

**20.2: An Improved Method for Measuring Display Motion Artifacts (11:20)**

*M. Wilson, M.C. Aoun*  
*Westar Display Technologies, Inc., Saint Charles, MO, U.S.A.*

Current methods for measuring motion artifacts under a condition known as smooth pursuit require a moving camera or high-speed camera. A simplified system using a stationary camera in which the image is moved electronically across the CCD surface during acquisition will be described.

**20.3: Quantitative Analysis of Image Sticking in LCDs (11:40)**

*S-C. Park, K-H. Lim, S-H. Choi, H-S. Soh*  
*LG.Philips LCD, Kyungbuk-do, Korea*

Three methods for analyzing and quantifying image sticking in LCDs (R\_SEMU, color difference, and luminance ratio) will be described. A new parameter, Non-Uniformity Value of the Panel (NVP), used to increase the accuracy of the image sticking analysis, will be described.

**LUNCH (12:00-2:1)**

**AUTHOR INTERVIEWS (6:30-7:30)**